



<b>Title of Change:</b>	Bump Location Change from Amkor T5 to ASEKH.																											
<b>Proposed first ship date:</b>	26 March 2019																											
<b>Contact information:</b>	Contact your local ON Semiconductor Sales Office or < <a href="mailto:ben.widsten@onsemi.com">ben.widsten@onsemi.com</a> >																											
<b>Samples:</b>	Contact your local ON Semiconductor Sales Office or < <a href="mailto:ben.widsten@onsemi.com">ben.widsten@onsemi.com</a> > Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.																											
<b>Additional Reliability Data:</b>	Contact your local ON Semiconductor Sales Office or < <a href="mailto:paul.syndergaard@onsemi.com">paul.syndergaard@onsemi.com</a> >																											
<b>Type of notification:</b>	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact < <a href="mailto:PCN.Support@onsemi.com">PCN.Support@onsemi.com</a> >																											
<b>Change Part Identification:</b>	Beginning with date code 1850 (parts marked with date code K50)																											
<b>Change Category:</b>	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input checked="" type="checkbox"/> Other <u>Wafer Bump</u>																											
<b>Change Sub-Category(s):</b>	<input type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input checked="" type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____																											
<b>Sites Affected:</b>	ON Semiconductor Sites: None	External Foundry/Subcon Sites: Amkor Taiwan T5 ASEKH																										
<b>Description and Purpose:</b>																												
We have changed the bump location from Amkor T5 to ASEKH.																												
The bump composition is also changing from SnAg (Ag = 2.3%) (old site) to SnAg (Ag = 1.8%) (new site)																												
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**Electrical Characteristic Summary:**

Electrical characteristics are not impacted.

**List of Affected Parts:**

Part Number	Qualification Vehicle
NCH-RSL10-101WC51-ABG	MD-RSL10-101WC51-AAG
PSWBC001A1C	

**NOTE:**

*Please be informed that there are Customer Specific parts impacted by this notice, thus MPN & CPN info will not be reflected in the parts list of this Generic document. Instead please click the link to the addendum copy provided in the email notification to see full list of affected products specific to your company.*